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Application No. <u>09/996,279</u>	Prepared by <u>NAB</u>	Tracking Number <u>06006908</u>	
Examiner-GAU <u>Pham-2814</u>	Date <u>10/11/04</u>	Week Date <u>9/6/04</u>	
	No. of queries <u>1</u>	<u>1FW (Rute)</u>	

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b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

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FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
(37 CFR 1.98(b))Attorney Docket No.:  
L&L-10178Applic. No.  
09/996,279

Applicant

Lothar Risch et al.

Filing Date  
November 28, 2001

Group Art Unit

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## U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
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## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES / NO
	J						
	K						
	L						
	M						
	N						

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	Pikus, F.G. et al.: "Nanoscale field-effect transistors: An ultimate size analysis", Appl. Phys. Lett. 1971, Vol. 25, December 22, 1997, pp. 3661-3663
	P	

EXAMINER

DATE CONSIDERED

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